

## **SIMS ANALYSIS OF NBO ON NB SAMPLES OF DIFFERENT OXYGEN CONTENT**

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### *Abstract*

Using a newly installed SIMS instrument at Cornell LEPP, we have carried out depth profile measurements on NbO/Nb content for various Nb samples: low and high RRR, inside an e-beam weld and in the heat affected zone, 100°C baked and unbaked samples prepared by EP and by BCP. High intensity and low intensity argon beams were used.

**NO SUBMISSION RECIEVED**